

Application/Control No.	Applicant(s)/Patent under Reexamination
10/716,871	KIM ET AL.
Examiner	Art Unit
Huyen X. Vo	2626

	SEAR	CHED	
Class	Subclass	Date	Examiner
704	270; 276	4/22/2007	HV
379	202.01	4/22/2007	HV
379	203.01	4/22/2007	HV
705	27	4/22/2007	HV

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
			-			

DATE 4/22/2007	EXMR HV
4/22/2007	HV